## Brammer Standard Company, Inc.

# Certificate of Analysis

#### **BS 0021**

Certified Reference Material<sup>1</sup> for 410 Stainless Steel Alloy (UNS Number \$41000)

	Certified Value <sup>2</sup>	Estimate of Uncertainty <sup>3</sup>	Certified Value <sup>2</sup>	Estimate of Ucertainty <sup>3</sup>	
		Analysis liste	ed as percent by weight		
С	0.128	0.003	V	0.029	0.002
Mn	0.420	0.006			
Р	0.021	0.001			
S	0.008	0.001	Informati	on Values <sup>4</sup>	
Si	0.354	0.008	As	0.004	
Cu	0.040	0.002	В	<0.0002	
Ni	0.100	0.004	Са	0.0002	
Cr	12.00	0.05	Nb	0.001	
Мо	0.016	0.001	0	0.004	
Al	0.008	0.001	Ti	0.003	
Co	0.015	0.001	W	0.005	
N	0.029	0.0015			
Sn	0.003	0.001			

<sup>&</sup>lt;sup>1</sup> Brammer Standard Company, Inc., is accredited by A2LA (Certificate Number 656.02) to ISO Guide 34 as a Reference Material Producer to produce Certified Reference Materials.

See the following pages for more information.

Certificate Number 0021-071801p1

<sup>&</sup>lt;sup>2</sup> The certified value listed is the present best estimate of the true value based on the results of an interlaboratory testing program.

 $<sup>^{3}</sup>$  The uncertainties listed are based on value judgments of the material inhomogeneity and the 95% confidence interval. The half-width confidence interval C(95%) is shown on page 2.

<sup>&</sup>lt;sup>4</sup> Information values are not certified and are provided for information only.

BS 0021				Data list	ed as	mass frac	tion ex	xpressed as	perc	ent.					0021-	071801p2		
Analysis	*	С	*	Mn	*	Р	*	S	*	Si	*	Cu	*	Ni	*	Cr	*	Мо
1	С	0.125	XRF	0.411	AIC	0.0193	С	0.0068	XRF	0.343	AIC	0.037	AIC	0.0956	TCr	11.9405	AIC	0.014
2	C	0.126	MnP	0.4143	XRF	0.020	C	0.007	XRF	0.348	AGX	0.039	GNi	0.096	XRF	11.968	AES	0.0147
3	C	0.127	MnP	0.415	AIC	0.020	C	0.0073	AIC	0.348	XRF	0.039	XRF	0.097	XRF	11.97	AIC	0.0149
4	C	0.1275	AIC	0.415	AIC	0.0202	C	0.00753	GSi	0.3486	XRF	0.039	AIC	0.097	TCr	11.98	AGX	0.015
5	C	0.13	XRF	0.419	AIC	0.0202	C	0.0077	XRF	0.350	ECS	0.039	MND	0.0978	XRF	11.991	AIC	0.016
6	C	0.130	AIC	0.421	XRF	0.0204	C	0.008	GSi	0.352	AIC	0.040	XRF	0.099	AIC	12.00	XRF	0.016
7	C	0.1302	AGX	0.421	AES	0.0207	ΙC	0.0080	AGA	0.357	AES	0.0402	XRF	0.10	TCr	12.01	XRF	0.016
8			XRF	0.422	AGA	0.0210	C	0.0082	AIC	0.361	AIC	0.0413	AGA	0.101	AIC	12.04	GMo	0.0162
9			AΑ	0.423	AIC	0.0213	C	0.0086	GSi	0.364	AIC	0.0415	XRF	0.102	XRF	12.065	XRF	0.0165
10			AIC	0.424	MPH	0.022			GSi	0.368	MCB	0.0420	AIC	0.105	TCr	12.07	MMo	0.0165
11			AES	0.427	MPN	0.0222					XRF	0.044	AIC	0.106				
12			MnP	0.428														
Average		0.1280		0.4200		0.0207		0.0077		0.3540		0.0402		0.0997		12.003		0.0156
Std Dev		0.0021		0.0053		0.0009		0.0006		0.0081		0.0019		0.0035		0.043		0.0009
Certified		0.128		0.420		0.021		0.008		0.354		0.040		0.100		12.00		0.016
t		2.4469		2.201		2.2281		2.306		2.2622		2.2281		2.2281		2.2622		2.2622
C (95%)		0.0020		0.0034		0.0006		0.0004		0.0058		0.0013		0.0024		0.031		0.0006

Analysis	*	Al	*	Со	*	N	*	Sn	*	v
2 3 4 5 6 7 8	AES AIC AES AES AGA AAA	0.0076 0.0079 0.008 0.008 0.008 0.0084 0.0084	AIC AAA XRF AES AGX AIC XRF M5 XRF	0.0140 0.0141 0.0141 0.0142 0.0145 0.0149 0.015 0.0154 0.0164 0.017 0.0170	FU TN FU FU FU FU FU	0.0290 0.02926 0.0293 0.0294 0.0295 0.0302 0.031	AES MSN AIC AIM AIC AES AAG AGA	0.004 0.0043	AAA AIC XRF XRF XRF AGX AES AES	0.0262 0.027 0.0280 0.028 0.028 0.029 0.029 0.029 0.0291 0.0305 0.0319 0.0331
Average		0.0080		0.0153		0.0293		0.0029		0.0291
Std Dev		0.0006		0.0012		0.0013		0.0011		0.0021
Certified		0.008		0.015		0.029		0.003		0.029
t		2.306		2.1788		2.3646		2.2281		2.2281
C(95%)		0.0004		0.0007		0.0011		0.0007		0.0014

Analysis	*	As	*	В	* Ca	* Nb	* 0	* Ti	* M
1 2 3 4 5		0.0039	AES AIC	<0.0002	AIC 0.0001 AES 0.00022	XRF 0.001 XRF 0.001 AES 0.0015 XRF 0.002	FU 0.0031 FU 0.00323 FU 0.0034 FU 0.0034 FU 0.007	AIC 0.0018 XRF 0.002 AES 0.0026 XRF 0.003 XRF 0.006	XRF 0.004 AES 0.004 MWC 0.0046 AIC 0.0048 XRF 0.005 XRF 0.005
Average		0.0040			0.0002	0.0014	0.0040	0.0031	0.0050
Std Dev		0.0001			0.0001	0.0005	0.0017	0.0017	0.0013
Information		(0.004)		(<0.0002)	(0.0002)	(0.001)	(0.004)	(0.003)	(0.005)

Data in parenth eses are not certified but are provided for information only.

 $C(95\%) = (t \times sd)/n$  The half-width confidence interval, where t is the appropriate Student's t value, sd is the interlaboratory standard deviation, and n is the number of acceptable mean values. For further information regarding the confidence interval for the certified value see ISO Guide 35:1989 section 4.

<sup>\*</sup> Methods of an alysis listed on page 3

### **Methods of Analysis**

Code	Element	Method
AA AAA AAG AES AGA AGX AIC AIH AIM		Flame Atomic Absorption Spectrometry Flame Atomic Absorption - standard addition method Electro-thermal atomization (graphite furnace) Atomic Absorption Spectrometry AES - Spark Source Optical Emission Spectrometry AES - Spark Source and Glow Discharge Spectrometry average Glow Discharge and X-Ray Fluorescence Spectrometry average AES - ICP -Inductively Coupled Plasma Spectrometry AES - ICP -Inductively Coupled Plasma Spectrometry after hydride generation AES - ICP Mass Spectrometry addition method
C	C, S	Combustion-Infrared Absorption (ASTM E 1019) traceable to CRMs
ECS	Cu	Sulphide precipitation, electro- deposition, gravimetric
FU	N, O	Inert gas Fusion Method (ASTM E 1019) traceble to CRMs
GMo GNi GSi	Mo Ni Si	Gravimetry, Benzolnoxime Dimethylglyoxime gravimetric Gravimetry with perchloric acid
IC	S	Ion chrometography
M5 MCB MM0 MND MnP MPH MPN MSn MVE MWC	Co Cu Mo Ni Mn P P Sn V	MAS - 5-Cl-PADAB spectrophotometric MAS - Bicyclohexane oxalyldihydrazone photometric MAS - Thiocyanate after extraction with butyl acetate MAS - Dimethylgloxime photometric MAS - Periodate oxidation MAS - Heteropoly molybdenum blue photometric MAS - n-butyol alcohol-trichloromethane extraction photometric MAS - Phenylfluorone photometric MAS - n-benzoyl phenylhydroxylamine extraction photometric MAS - Chlorpromazine hydrochloride sodium thiocyanate - tri-chloromethane extraction
TCr TN	Cr N	Persulfate oxidation, ferrous sulfate titrimetric Neutralization titrimetric after distillation separation
XRF		X-Ray Fluorescence spectrometry

AES = Atomic Emission Spectrom etry

 $MAS = M \ olecular \ Absorption \ Spectrometry \ (photometric, \ spectrophotometric \ methods)$ 

#### Co-operating Laboratories: The co-operating laboratories were:

Laboratory	Laboratory contact
Allvac, Lockport, New York	Thomas Herdlein
Allvac, Monroe, North Carolina	Patrick M. Cole
ANAREM, Prague, Czech Republic	Karel Bi ovsk
Brammer Standard Co., Inc., Houston, Texas	Richard P. Beaumont
China National Analysis Center for Iron and Steel, Beijing, China	Prof. Wang Haizhou
Crucible Specialty Steel, Syracuse, New York	William Mastroe
J. Dirats and Co., Inc., Westfield, Massachusetts	Eric E. Dirats
IncoTest, Huntington, West Virginia	Melissa G. Staley
LECO Corporation, St. Joseph, Michigan	Dennis Lawrenz
Shiva Analyticals (India) Ltd., Hoskote, Bangalore, India	Dr. T. V. Ramakrishna
VHG Laboratories, Inc., Manchester, New Hampshire	Julie M. McIntosh

**Additional analytical data**: This material was used as an unknown test specimen number 0021 in a nationally recognized Proficiency Testing Program (PTP) for stainless steel. Most of the participating laboratories used one or more of the ASTM Standard Test Methods E 572, E 1019, and E 1086. The PTP data was not used in calculating the certified values listed on pages 1 and 2. The data shown below are the results from the PTP.

Combustion Instrument Analysis using ASTM Standard Test Method E 1019

	С	S	N	О
Number of Labs	26	25	22	21
Grand Average	0.1279	0.0078	0.0299	0.0036
Standard Deviation	0.0049	0.0008	0.0009	0.0008

Optical Emission Spectrometric Analysis using ASTM Standard Test Method E 1086

	C	Mn	P	S	Si	Cu	Ni
Number of Labs Grand Average Standard Deviation	18 0.1320 0.0048	23 0.4175 0.0093	22 0.0209 0.0009	17 0.0074 0.0010	22 0.3568 0.0092	21 0.0387 0.0047	17 0.0994 0.0067
	C		~				
	Cr	Мо	Co	V	Al		

X-ray Emission Spectrometric Analysis using ASTM Standard Test Method E 572

	Mn	P	Si	Cu	Ni	Cr	Mo	V	Co
Number of Labs	16	8	10	14	17	17	17	9	16
Grand Average	0.4141	0.0205	0.3527	0.0385	0.0973	12.0322	0.0169	0.0297	0.0166
Standard Deviation	0.0069	0.0013	0.0100	0.0026	0.0054	0.0780	0.0021	0.0030	0.0033

**Certification Process**: The requirements of ISO Guide 31, ISO Guide 34, ISO Guide 35, and ASTM Standard Guides E 1724 and E 1831 were followed for the preparation of this reference material and certificate of analysis. This is a Certified Reference Material as defined by ISO Guide 30.

**Analysis**: Chemical analyses were made on chips prepared by a lathe from the certified portion of the discs in accordance with ASTM Standard Practice E 1806. The laboratories participating in the testing normally followed the requirements of ISO Guide 25 and/or ISO Standard 17025. Individual values listed on page 2 are the average of each analyst's results. Methods of analysis are listed on page 3.

**Outliers:** Some outlying data was excluded from the data listed on page 2 due to technical assessment of the cooperating laboratories and statistical evaluation.

**Traceability:** The following Certified Reference Materials were used to validate the analytical data listed on page 2: SRM 20f, 125b, 131f, 155, 2159, 2160, 3013a, 3107, 3109a, 3161a; ECRM 096-1, 289-1, 295-1; BCS 152/3, 338, 431/1.

**Homogeneity**: This Certified Reference Material was tested for homogeneity using ASTM Standard Method E 826 and found acceptable. It was also examined by optical emission spectrometry using ASTM Standard Test Method E 1086 and found to be compatible with the following Reference Materials: SRM 1219, 1267, C1289, 1295; JSS 650-8; BS SS 4951, 91E, 410A.

Validity statement: ISO Guide 31 states that the certificate of analysis should contain an expiration date for all materials where instability has been demonstrated or is considered possible, after which the certified value is no longer guaranteed by the certifying body. Whereas this material is in a solid form and stable, no expiration date is specified.

**Source**: This material was produced by the Gloria Heavy Industrial Corporation, Tainan Hsien, Taiwan. It was melted by an electric arc furnace, bottom poured into ingots, hot rolled, and finished with a normalized heat treatment.

Form: This Certified Reference Material is in the form of a disc, approximately 40 mm in diameter and 12 mm thick.

Use: This Certified Reference Material is intended for use in optical emission and x-ray spectrometric methods of analysis. Refer to ISO Guide 33 for information about the use of Reference Materials.

Certified area: The entire depth of the disc may be used.

**Caution:** As with any bar material, avoid optical emission spectrometric burns in the center of the disc (5 mm radius), as some segregation may be present.

**Sample Preparation**: For best analytical results, use the same method for preparing the analytical surface on all reference materials as you use for production specimens. Avoid overheating the disc during surface preparation.

Certificate Number: The unique identification number for this certificate of analysis is 0021-071801-px, where x indicates the page number. Refer to future Brammer Standard Company catalogs for information on any revisions to this or other Brammer Standard reference materials. You may also obtain information on revisions of certificates from the internet at brammerstandard.com.

**Safety Notice:** A Material Safety Data Sheet (MSDS) is not required for this material. This material will not release or otherwise result in exposure to a hazardous chemical under normal conditions of use. Inquiries concerning this Reference Material should be directed to:

Brammer Standa 14603 Benfer Ro	,	Pnone:	(281) 440-9396	web	brammerstandard.com
	77069-2895 USA	Fax:	(281) 440-4432	e-mail	bramstan@netropolis.net
Certified by:			on July 18, 2001.		
	G. R. Brammer				

Brammer Standard Company, Inc., is accredited to ISO Guide 34 as a Reference Material Producer for the production of Certified Reference Materials and Reference Materials by A2LA (Certificate Number 656.02) The scope of accreditation is listed on the website: www.brammerstandard.com

By Certificate Number 10539, the Quality System of Brammer Standard Company, Inc., is registered to ISO 9002:1994 by National Quality Assurance, U.S.A.

Brammer Standard Company's Chemical Laboratory is accredited to ISO Guide 25 by A2LA. (Certificate Number 656.01)

#### References:

ASTM documents available from ASTM, 100 Barr Harbor Drive, West Conshohocken, PA 19428-2959, Telephone: 610-832-9500 Fax: 610-832-9555 e-mail: service@astm.org Website: www.astm.org

E 572 - 94 Standard Test Method for X-Ray Emissioin Spectrometric Analysis of Stainless Steel

E 826 - 85 (Reapproved 1996) Standard Practice for Testing Homogeneity of Materials for the Development of Reference Materials

E 1019 - 2000 Standard Test Methods for Determination of Carbon, Sulfur, Nitrogen, and Oxygen in Steel and in Iron, Nickel, and Cobalt Alloys

E 1086 - 94 Standard Test Method for Optical Emission Vacuum Spectrometric Analysis of Stainless Steel by the Point-to-Plane Excitation Technique

E 1724 - 95 Standard Guide for Testing and Certification of Metal and Metal-Related Reference Materials

E 1806 - 96 Standard Practice for Sampling Steel and Iron for Determination of Chemical Composition

E 1831 - 96 Standard Guide for Preparing Certificates for Reference Materials Relating to Chemical Composition of Metals, Ores, and Related Materials.

ISO Guides available from Global Engineering - www.global.ihs.com

ISO Standard 17025 (First edition, 1999), General requirements for the competence of calibration and testing laboratories.

ISO Guide 25 (Third edition, 1990), General requirements for the competence of calibration and testing laboratories.

ISO Guide 30 (Second edition, 1991), Terms and definitions used in connection with reference materials.

ISO Guide 31 (Second edition, 2000), Reference materials -Contents of certificates and labels.

ISO Guide 33 (Second edition, 2000), Uses of certified reference materials.

ISO Guide 34 (Second edition, 2000), General requirements for the competence of reference material producers.

ISO Guide 35 (Second edition, 1989), Certification of reference materials - General and statistical principles.

Other useful documents available from NIST, U.S. Department of Commerce, Gaithersburg, MD 20899.

NIST Special Publication 260-100, Handbook for SRM Users

NIST Special Publication 829, Use of NIST Standard Reference Materials for Decisions on Performance of Analytical Chemical Methods and Laboratories

Certificate Number 0021-071801p6